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| APPLICATION NO. | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|--|-------------|----------------------|---------------------------------|------------------------|
| 10/644,225 | 08/19/2003 | Igor Keller | CA7017522001 | 6463 |
| 23639 7590 09/28/2007 BINGHAM MCCUTCHEN LLP Three Embarcadero Center San Francisco, CA 94111-4067 | | | EXAMINER PIERRE LOUIS, ANDRE | |
| | | | ART UNIT 2123 | PAPER NUMBER |
| | | | MAIL DATE 09/28/2007 | DELIVERY MODE PAPER |

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

| | | | |
|------------------------------|--------------------------------|------------------------------|--|
| Office Action Summary | Application No. 10/644,225 | Applicant(s) KELLER, IGOR | |
| | Examiner Andre Pierre-Louis | Art Unit 2123 | |

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 14 September 2007.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-41 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-41 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 09/14/2007 has been entered.
2. Claims 1-41 have been presented for examination.

Response to Arguments

3. Applicant's arguments filed 09/14/2007 have been fully considered but they are not persuasive.

3.1 Regarding Applicant's assertion that "there is no consideration or discussion explicit or implied of slew rate in the late method, and that Lee et al. fails to teach each and every limitation of the present claims in the matter recited therein", the Examiner respectfully disagrees and notes that Lee et al. teaches a method and apparatus for performing worst-case transition for timing signal analysis purposes including determining a first and second slew values at the gate (*see abstract, for example and col.2 lines 16-44*). Lee et al. goes on to disclose that a representative signal is determined at the gate including an arrival time and a slew rate (*see abstract, also see col.2 lines 16-33, just to name a few*). However, the cited reference is clearly mapped to the instant and fully supports the Examiner's rejection, as evidenced by the rejection below. Lee et al. continues to disclose that a slew signal is determined using the combination of slew and arrival time (*see col.6 lines 31-39*), determined a worst-case arrival time and signal propagation (*see col.3 lines 32-col.4 lines 43 and fig.11*).

3.2 While the applicant believes that the independent claims, along with the dependent claims should be found allowable, the examiner respectfully disagrees and asserts that the combined references cited teach the entire claimed invention, as evidenced by the grounds of rejection below. Applicant is further encouraged to look at the references cited not used shown in the conclusion section of this and the previous action. However, the grounds of rejections below fully support the Examiner's position in rejecting the instant claims.

Claim Rejections - 35 USC § 102

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

4.0 Claims 1-41 are rejected under 35 U.S.C. 102(b) as being anticipated by Lee et al. (U.S. Patent No. 6,430,731).

4.1 In considering the independent claims 1,6, 11, 19, 29, and 33, Lee et al. teaches Beakes et al. substantially teaches a method for determining a worst-case transition, and particularly teaches the steps of determining at least a plurality of different arrival times and a plurality of different slews from a plurality of timing events propagated to an input of a gate of based on a timing model of the gate (*col.2 lines 16-33 and col.4 line 9-col.5 line 5; also see col.7 lines 4-10*); selecting one of the plurality of timing events as a worst case timing event based on at least a combination of an arrival time in the plurality of the different arrival times and a slew of the plurality of different slews of the plurality of timing events (*fig.11 col.7 lines 25-31 and col.14 lines 25-43; also see col.15 lines 44-48*); storing information related to the worst case timing event (*col.14 lines 40-43 and col.15 lines 52-62*).

4.2 As per claims 2,7, 12, and 20, Lee et al. teaches the step of determining a plurality of gate delays for a plurality of input signals based on the timing model of the gate (*see Lee et al. col.4 lines 27-43*).

4.3 With regards to claims 3,8, 13, and 21, Lee et al. teaches that the step of selecting the worst-case input timing event further comprises the step of selecting a worst delay based on the gate delays (*see Lee et al. col.15 lines 44-48*).

4.4 Regarding claims 4,9, 14, and 22, Lee et al. teaches that the timing model comprises $To = Ti + Dg$, $Dg = F(Si, C)$, $So = Q(Si, C)$, where To is an output time, Ti is an input time, Dg is a gate delay, Si is an input slew, C is a capacitive load of the gate, and So is an output slew, wherein the delay Dg of the gate depends, at least in part, on the slew of the input transition and capacitive load at the output of the gate (*see Lee et al. col.4 lines 27-43*).

4.5 Regarding claims 5,10, 15, and 23, Lee et al. teaches that the timing model is a timing library format (FTL) model (*see Lee et al. col.5 lines 7-17*).

4.6 With regards to claims 16-18, Lee et al. teaches that the output slews of the output timing events includes slew rate of the output timings, which is determined by an amount of time for a waveform to transition from a first voltage to a second voltage (*see Lee et al. col.2 lines 16-33*).

4.7 Regarding claim 24, Lee et al. teaches that the different arrival times comprise the arrival times of the timing event at each input of the gate (*see Lee et al. col.2 lines 16-33 and col.4 lines 9-43*).

4.8 As per claim 25, Lee et al. teaches that the different arrival times of the timing event at each input of the gate comprises the input times of the timing events (*see Lee et al. col.2 lines 16-33 and col.4 lines 9-43*).

5.9 With regards to claims 26,30, and 34, Lee et al. teaches that the different slews comprise transition times of the timing events through the gate (*see Lee et al. col.3 line 65-col.4 lines 43*).

4.10 Regarding claims 27,31, and 35, Lee et al. teaches that the transition times of the timing events through the gate are based on characteristics of the gate (*see Lee et al. col.3 line 65-col.4 lines 43*).

4.11 As per claims 28,32, and 36, Lee et al. teaches that a duration of the transition times of the timing events through the gate is based on characteristics of the gate (*see Lee et al. col.3 line 65-col.4 lines 43*).

4.12 With regards to claims 37-41, Lee et al. teaches that information related to the worst-case timing event is stored in a memory (*see Lee et al. col.14 lines 40-43 and col.15 lines 52-62*).

Conclusion

5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

5.1 Lim et al., Accurate Worst Case Timing Analysis Techniques for RISC Processor, IEEE 1994.

5.2 Malik et al., Static Timing Analysis of Embedded Software, 1997.

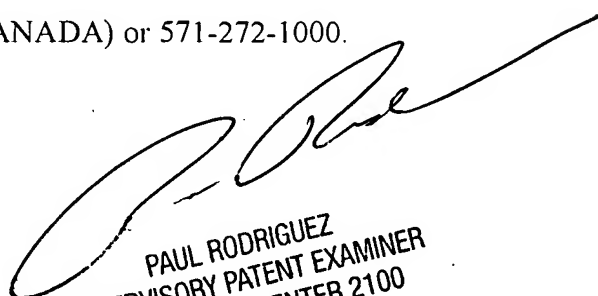
6. Claims 1-41 are rejected and **THIS ACTION IS Non-FINAL**. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Andre Pierre-Louis whose telephone number is 571-272-8636. The examiner can normally be reached on Mon-Fri, 8:00AM-4:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Paul L. Rodriguez can be reached on 571-272-3753. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

September 25, 2007

APL



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